ES_LPC2367

Errata sheet LPC2367

Rev. 6 — 20 April 2011

Errata sheet

Document information

Info	Content
Keywords	LPC2367 errata
Abstract	This errata sheet describes both the known functional problems and any deviations from the electrical specifications known at the release date of this document.
	Each deviation is assigned a number and its history is tracked in a table at the end of the document.

Revision history

Rev	Date	Description
6	20110420	• Added Note.2.
5	20110301	• Added ADC.1.
4	20100401	• The format of this errata sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. • Added Ethernet.1
3	20100122	• Added VBAT.2
2	20090512	• Added Rev D
1	20080904	• First version

Contact information

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1. Product identification

The LPC2367 devices typically have the following top-side marking:

LPC2367xxx

xxxxxxx

xxYYWWR[x]

The last/second to last letter in the third line (field 'R') will identify the device revision. This Errata Sheet covers the following revisions of the LPC2367:

Table 1. Device revision table

Revision identifier (R)	Revision description
'A'	Second device revision
'B'	Third device revision
'D'	Fourth device revision

Field 'YY' states the year the device was manufactured. Field 'WW' states the week the device was manufactured during that year.

2. Errata overview

Table 2. Functional problems table

Functional problems	Short description	Revision identifier	Detailed description
Ethernet.1	Ethernet TxConsumeIndex register does not update correctly after the first frame is sent	'A', 'B', 'D'	Section 3.1 on page 5
Core.1	Incorrect update of the Abort Link register in Thumb state	'A', 'B', 'D'	Section 3.2 on page 5
Flash.1	Operating speed out of on-chip flash is restricted	'A'	Section 3.3 on page 6
MAM.1	Code execution failure can occur with MAM Mode 2	'A'	Section 3.4 on page 7
Deep power-down.1	Deep power-down mode is not functional	'A', 'B'	Section 3.5 on page 7
VBAT.1	Increased power consumption on VBAT when VBAT is powered before the 3.3 V supply used by rest of device	'A', 'B'	Section 3.6 on page 7
VBAT.2	The VBAT pin cannot be left floating	'A', 'B'	Section 3.7 on page 8
ADC.1	External sync inputs not operational	'A', 'B', 'D'	Section 3.8 on page 9

Table 3. AC/DC deviations table

AC/DC deviations	Short description	Revision identifier	Detailed description
n/a	n/a	n/a	n/a

Table 4.   Errata notes table

Errata notes	Short description	Revision identifier	Detailed description
Note.1	When the input voltage is Vi $\geq$ V$_{DD}$ I/O + 0.5 V on each of the following port pins P0.23, P0.24. P0.25, P0.26, P1.30, and P1.31 (configured as general purpose input pin (s)), current must be limited to less than 4 mA by using a series limiting resistor.	'A', 'B', 'D'	<u>Section 5.1 on page 10</u>
Note.2	On the LPC2367 Rev D, design changes to the Memory Accelerator Module were made to enhance timing and general performance.	'D'	<u>Section 5.2 on page 10</u>

3. Functional problems detail

3.1 Ethernet.1: Ethernet TxConsumeIndex register does not update correctly after the first frame is sent

Introduction:

The transmit consume index register defines the descriptor that is going to be transmitted next by the hardware transmit process. After a frame has been transmitted hardware increments the index, wrapping the value to 0 once the value of TxDescriptorNumber has been reached. If the TxConsumeIndex equals TxProduceIndex the descriptor array is empty and the transmit channel will stop transmitting until software produces new descriptors.

Problem:

The TxConsumeIndex register is not updated correctly (from 0 to 1) after the first frame is sent. After the next frame sent, the TxConsumeIndex register is updated by two (from 0 to 2). This only happens the very first time, so subsequent updates are correct (even those from 0 to 1, after wrapping the value to 0 once the value of TxDescriptorNumber has been reached)

Work-around:

Software can correct this situation in many ways; for example, sending a dummy frame after initialization.

3.2 Core.1: Incorrect update of the Abort Link register in Thumb state

Introduction:

If the processor is in Thumb state and executing the code sequence STR, STMIA or PUSH followed by a PC relative load, and the STR, STMIA or PUSH is aborted, the PC is saved to the abort link register.

Problem:

In this situation the PC is saved to the abort link register in word resolution, instead of half-word resolution.

Conditions:

The processor must be in Thumb state, and the following sequence must occur:

<any instruction>

<STR, STMIA, PUSH> <---- data abort on this instruction

LDR rn, [pc,#offset]

In this case the PC is saved to the link register R14_abt in only word resolution, not half-word resolution. The effect is that the link register holds an address that could be #2 less than it should be, so any abort handler could return to one instruction earlier than intended.

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Work-around:

In a system that does not use Thumb state, there will be no problem.

In a system that uses Thumb state but does not use data aborts, or does not try to use data aborts in a recoverable manner, there will be no problem.

Otherwise the workaround is to ensure that a STR, STMIA or PUSH cannot precede a PC-relative load. One method for this is to add a NOP before any PC-relative load instruction. However this is would have to be done manually.

3.3 Flash.1: Operating speed out of on-chip flash is restricted

Introduction:

The operating speed of this device out of internal flash/SRAM is specified at 72 MHz.

Problem:

Code execution from internal flash is restricted depending upon the device revision:

1. Rev 'A' devices: Code execution from internal flash is restricted to a maximum of 60 MHz.

For example, use a PLL output frequency of F_{CCO} = 360 MHz and divide it by 6 (CCLKSEL = 5) to generate 60 MHz CPU clock (Do not use even values for CCLKSEL).

Considering the example (Input crystal-12 MHz, N = 1, M = 12): F_{CCO} = 288 MHz

The CPU Clock Configuration register (located at 0xE01F C104) can then be used to divide this frequency by 6 (CCLKSEL = 5) to achieve 48 MHz. Since this register only accepts odd values for CCLKSEL, a division by 5 (CCLKSEL = 4) is not a valid option.

In both the above revisions, code can still execute out of SRAM at up to 72 MHz.

Work-around:

None.

3.4 MAM.1: Under certain conditions in MAM Mode 2 code execution out of internal flash can fail

Introduction:

The MAM block maximizes the performance of the ARM processor when it is running code in flash memory. It includes three 128-bit buffers called the Prefetch Buffer, the Branch Trail Buffer and the data buffer. It can operate in 3 modes; Mode 0 (MAM off), Mode 1 (MAM partially enabled) and Mode 2 (MAM fully enabled).

Problem:

Under certain conditions when the MAM is fully enabled (Mode 2) code execution from internal flash can fail. The conditions under which the problem can occur is dependent on the code itself along with its positioning within the flash memory.

Work-around:

If the above problem is encountered then Mode 2 should not be used. Instead, partially enable the MAM using Mode 1.

3.5 Deep power-down.1: Deep power-down mode is not functional

Introduction:

Deep power-down mode is like Power-down mode, but the on-chip regulator that supplies power to internal logic is also shut off. This produces the lowest possible power consumption without actually removing power from the entire chip.

Problem:

The power consumption in Deep power-down mode does not meet the specifications.

Work-around:

None.

3.6 VBAT.1: Increased power consumption on VBAT when VBAT is powered before the 3.3 V supply used by rest of the device

Introduction:

The device has a VBAT pin which provides power only to the RTC and Battery RAM. VBAT can be connected to a battery or the same 3.3 V supply used by rest of the device ($V_{DD(3V3)}$ pin, $V_{DD(DCDC)(3V3)}$ pin).

Problem:

If VBAT is powered before the 3.3 V supply, VBAT is unable to source the start-up current required for the Battery RAM. Therefore, power consumption on the VBAT pin will be high and will remain high until 3.3 V supply is powered up. Once 3.3 V supply is powered up, power consumption on the VBAT pin will reduce to normal and subsequent power cycle on the 3.3 V supply will not cause an increased power consumption on the VBAT pin.

Work-around:

Provide 3.3 V supply used by rest of the device first and then provide VBAT voltage.

3.7 VBAT.2: The VBAT pin cannot be left floating

Introduction:

The device has a VBAT pin which provides power only to the Real Time Clock (RTC) and Battery RAM. VBAT can be connected to a battery or the same supply used by rest of the device ($V_{DD(3V3)}$ pin, $V_{DD(DCDC)(3V3)}$ pin). The input voltage range on the VBAT pin is 2.0 V minimum to 3.6 V maximum for temperature −40 °C to +85 °C. Normally, if the RTC and the Battery RAM are not used, the VBAT pin can be left floating.

Problem:

If the VBAT pin is left floating, the internal reset signal within the RTC domain may get corrupted and as a result, prevents the device from starting-up.

Work-around:

The VBAT should be connected to a battery or the same supply used by rest of the device ($V_{DD(3V3)}$ pin, $V_{DD(DCDC)(3V3)}$ pin).

3.8 ADC.1: External sync inputs not operational

Introduction:

In software-controlled mode (BURST bit is 0), the 10-bit ADC can start conversion by using the following options in the A/D Control Register:

26:24	START		When the BURST bit is 0, these bits control whether and when an A/D conversion is started:	0
		000	No start (this value should be used when clearing PDN to 0).	
		001	Start conversion now.	
		010	Start conversion when the edge selected by bit 27 occurs on P2.10/EINT0.	
		011	Start conversion when the edge selected by bit 27 occurs on P1.27/CAP0.1.	
		100	Start conversion when the edge selected by bit 27 occurs on MAT0.1.	
		101	Start conversion when the edge selected by bit 27 occurs on MAT0.3.	
		110	Start conversion when the edge selected by bit 27 occurs on MAT1.0.	
		111	Start conversion when the edge selected by bit 27 occurs on MAT1.1.	

Fig 1.   A/D control register options

Problem:

The external start conversion feature, AD0CR:START = 0x2 or 0x3, may not work reliably and ADC external trigger edges on P2.10 or P1.27 may be missed. The occurrence of this problem is peripheral clock (pclk) dependent. The probability of error (missing a ADC trigger from GPIO) is estimated as follows:

- For PCLK_ADC = 72 MHz, probability error = 12 %
- For PCLK_ADC = 50 MHz, probability error = 6 %
- For PCLK_ADC = 12 MHz, probability error = 1.5 %

The probability of error is not affected by the frequency of ADC start conversion edges.

Work-around:

In software-controlled mode (BURST bit is 0), the START conversion options (bits 26:24 set to 0x1 or 0x4 or 0x5 or 0x6 or 0x7) can be used. The user can also start a conversion by connecting an external trigger signal to a capture input pin (CAPx) from a Timer peripheral to generate an interrupt. The timer interrupt routine can then start the ADC conversion by setting the START bits (26:24) to 0x1. The trigger can also be generated from a timer match register.

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4. AC/DC deviations detail

4.1 n/a

5. Errata notes detail

5.1 Note.1

On each of the following port pins P0.23, P0.24, P0.25, P0.26, P1.30, and P1.31 (when configured as general purpose input pin (s)), leakage current increases when the input voltage is Vi $\geq$ V$_{DD}$ I/O + 0.5 V. Care must be taken to limit the current to less than 4 mA by using a series limiting resistor.

5.2 Note.2

On the LPC2367 Rev D, design changes to the Memory Accelerator Module were made to enhance timing and general performance. Design changes are intended to enhance performance in general and will result in minor differences in the code execution timing between the previous device revisions and rev D. Actual performance impact is code dependent, some code sequences may speed up while other code sequences may slow down between the previous device revisions and rev D. This might be observed when using software delays and in such cases, a hardware timer should be used to generate a delay instead of a software delay.

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